

<b>Notice of References Cited</b>	Application/Control No. 09/835,300	Applicant(s)/Patent Under Reexamination KIMBLE, DAVID MICHAEL	
	Examiner Son P. Huynh	Art Unit 2611	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,449,653	09-2002	Klemets et al.	709/231
	B	US-6,317,885	11-2001	Fries, Robert M.	725/109
	C	US-2003/0149988	08-2003	Ellis et al.	725/87
	D	US-2002/0009149	01-2002	Rodriguez et al.	375/240.25
	E	US-6,539,437	03-2003	Windheim et al.	719/330
	F	US-6,219,042	04-2001	Anderson et al.	715/716
	G	US-6,526,580	02-2003	Shimomura et al.	725/63
	H	US-6,842,906	01-2005	Bowman-Amuah, Michel K.	719/330
	I	US-6,081,263	06-2000	LeGall et al.	715/760
	J	US-6,591,305	07-2003	Densmore, Owen	709/245
	K	US-6,640,239	10-2003	Gidwani, Sanjay M.	709/203
	L	US-6,292,834	09-2001	Ravi et al.	709/233
	M	US-5,918,012	06-1999	Astiz et al.	709/217

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	EP 0 872 987 A2	10-1998	EP	Seki	H04L 29/06
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.